Twenty four people were in attendance at the May 24, 2012 NCSLI section meeting held at Promega Corporation, in Madison, Wisconsin. Promega’s metrology department sponsored the meeting and provided outstanding facilities, plus morning and afternoon snacks.

The meeting got started by the Madison section coordinator, Jay Bucher, who welcomed everyone, and opened the meeting by having all the attendees give their name, company and what they do. After the introductions, the program got underway.

Our first presenters were John Roethke from Exact Sciences, and Keela Sniadach from Promega Corporation, who pooled their resources to give us a presentation entitled: “Gage Repeatability and Reproducibility: A Workshop in Measurement Variation using Pipette Calibration to demonstrate Key Features of Analysis of Variation.” John discussed the various aspects of Gage R&R, and the different parts of the math involved. Keela demonstrated the calibration of pipettes, hands on I might add, and then had two volunteers do the same so that John had the required data to help explain the process to the attendees. Todd Edeker from the USDA and Karl Wigdal from Promega volunteered to see how accurate their thumbs were and each calibrated five pipettes. The attendees were very interested in how the calibration system that Promega uses worked, including the logistics concerned with the balance and software interfacing.

After their presentation, which was completed well under the allotted time, and a short break, Jay Bucher from Bucherview Metrology Services gave a presentation entitled “Basic Training for New Calibration Technicians in the Biopharma & Medical Device Industries.” Again, a well received presentation with lots of discussion and
interest. It was immediately followed by Walter Nowocin from Medtronic, Inc., who drove all the way down from the Twin Cities. Walter's presentation, “The Top 10 List – Best Lessons Learned from FDA Warning Letters,” also drew many questions and enhanced the discussion among attendees. Walter and Jay had previously gone back to back at the 2012 Measurement Science Conference with like results; similar topics approached from different perspectives that complemented each other.

We took a group picture and again ensured all the attendees received a door prize. The latest edition of *The Metrology Handbook, Second Edition* had just been published the previous week, so Jay was able to get three copies from the Measurement Quality Division of ASQ as door prizes, along with donated items from Bucherview Metrology Services, Promega Corporation and JH Metrology. Special thanks to the first time attendees who we hope will join us for future section meetings, and a very special thank you to Walter for taking time to present here in Madison.

Our next section meeting will be in the late fall of 2012, and we look forward to seeing everyone again. Thanks again to those that took the time to prepare and present such well received and discussed presentations and topics.

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